



INSULATED GATE BIPOLAR TRANSISTOR

$$V_{CES} = 1200V$$

$$I_{C(Nominal)} = 15A$$

$$T_{J(max)} = 175^{\circ}C$$

$$V_{CE(on)} typ = 1.9V @ I_{C} = 15A$$

G n-channel

G C E Gate Collector Emitter

Applications

- Induction Heating
- Microwave Ovens
- Welding Machines
- Soft Switching Applications
- Motor Drives
- UPS
- HEV Inverters

Features	→ Benefits
Low V _{CE(ON)} and Switching Losses	High efficiency in a wide range of applications and switching frequencies
Square RBSOA and Maximum Junction Temperature 175°C	Improved Reliability due to rugged hard switching performance and higher power capability
Positive V _{CE (ON)} Temperature Coefficient	Excellent current sharing in parallel operation

Paga naut numbar	Dookogo Typo	Standa	rd Pack	Ordereble pert number
Base part number	Package Type	Form	Quantity	Orderable part number
IRG7CH28UEF	Die on film	Wafer	1	IRG7CH28UEF

Mechanical Parameter

Die Size	3.69 x 3.69	mm ²			
Minimum Street Width	75	μm			
Emiter Pad Size (Included Gate Pad)	See Die Drawing				
Gate Pad Size	0.5 x 0.5	mm ²			
Area Total / Active	13.6 / 5.9				
Thickness	120	μm			
Wafer Size	200	mm			
Notch Position	0	Degrees			
Maximum-Possible Chips per Wafer	2033 pcs				
Passivation Front side	Silicon Nitride				
Front Metal	Al, Si (4μm)	Al, Si (4μm)			
Backside Metal	Al- Ti - Ni- Ag (1kA°-1kA°-4kA°-6kA°)				
Die Bond	Electrically conductive epoxy or solder				
Reject Ink Dot Size	0.25 mm diameter minimum				



Maximum Ratings

	Parameter	Max.	Units
V_{CE}	Collector-Emitter Voltage, T _J =25°C	1200	V
I_{C}	DC Collector Current	①	Α
I _{LM}	Clamped Inductive Load Current ②	60	Α
$V_{\sf GE}$	Gate Emitter Voltage	± 30	V
T_{J}, T_{STG}	Operating Junction and Storage Temperature	-40 to +175	°C

Static Characteristics (Tested on wafers) @ T_J=25°C

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	1200				$V_{GE} = 0V, I_C = 100\mu A$ ③
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage		1.3	1.55	V	$V_{GE} = 15V, I_{C} = 2.5A, T_{J} = 25^{\circ}C$
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	3.0		6.0		$I_C = 350 \mu A$, $V_{GE} = V_{CE}$
I _{CES}	Zero Gate Voltage Collector Current		1.0	25	μΑ	$V_{CE} = 1200V, V_{GE} = 0V$
I_{GES}	Gate Emitter Leakage Current			± 100	nΑ	$V_{CE} = 0V$, $V_{GE} = \pm 30V$

Electrical Characteristics (Not subject to production test- Verified by design/characterization)

	Parameter	Min.	Тур.		Units	Conditions
	0 11 1 15 111 0 1 1 1 1 1 1		1.9	2.2	.,	$V_{GE} = 15V, I_C = 15A, T_J = 25^{\circ}C$ ④
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage		2.45		V	$V_{GE} = 15V, I_{C} = 15A, T_{J} = 175^{\circ}C^{\oplus}$
RBSOA	Reverse Bias Safe Operating Area	FUL	FULL SQUARE			$T_J = 150$ °C, $I_C = 60$ A $V_{CC} = 960$ V, $V_D \le 1200$ V $Rg = 100\Omega$, $V_{GE} = +20$ V to 0V
C _{iss}	Input Capacitance		1160			$V_{GE} = 0V$
C _{oss}	Output Capacitance		40		рF	$V_{CE} = 30V$
C_{rss}	Reverse Transfer Capacitance		25			f = 1.0MHz
Q_g	Total Gate Charge (turn-on)	_	60			I _C = 15A
Q_{ge}	Gate-to-Emitter Charge (turn-on)	_	10	_	nC	$V_{GE} = 15V$
Q_{gc}	Gate-to-Collector Charge (turn-on)	_	30	_		$V_{CC} = 600V$

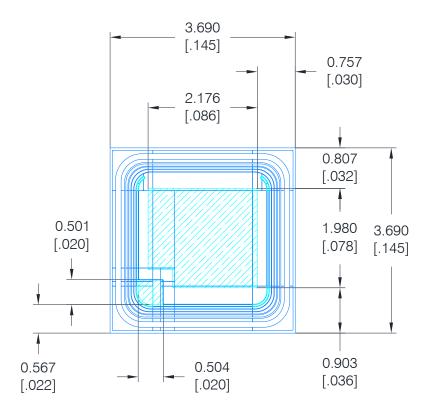
Switching Characteristics (Inductive Load-Not subject to production test-Verified by design/characterization)

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	Parameter	Min.	Тур.	Max.	Units	Conditions ®
t _{d(on)}	Turn-On delay time	_	35	_		$I_C = 15A, V_{CC} = 600V$
t _r	Rise time	_	20	_		$R_G = 22\Omega$, $V_{GE}=15V$, L=1.0mH
t _{d(off)}	Turn-Off delay time	_	225	_		$T_J = 25^{\circ}C$
t _f	Fall time	_	105	_	no	
$t_{d(on)}$	Turn-On delay time	_	30	_	ns	$I_C = 15A, V_{CC} = 600V$
t _r	Rise time	_	20			$R_G = 22\Omega$, $V_{GE}=15V$, $L=1.0mH$
t _{d(off)}	Turn-Off delay time	_	225			T _J = 175°C
t _f	Fall time	_	165			

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Die Drawing



NOTES:

- 1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 2. CONTROLLING DIMENSION: INCHES
- 3. DIE WIDTH AND LENGTH TOLERANCE: +0, -0.0508 [+0, -0.002]
- 4. DIE THICKNESS = 0.120 [.0047]

REFERENCE: IRG7CH28UB

Notes:

- \odot The current in the application is limited by T_{JMax} and the thermal properties of the assembly.
- $@~V_{CC}=80\%~(V_{CES}),~V_{GE}=20V,~L=60\mu H,~R_{G}=100\Omega.$
- ④ Die Level Characterization.
- © Values influenced by parasitic L and C in measurement.



Additional Testing and Screening

For Customers requiring product supplied as Known Good Die (KGD) or requiring specific die level testing, please contact your local IR Sales.

Shipping

Sawn Wafer on Film. Please contact your local IR sales office for non-standard shipping options

Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.
- Singulated die are not to be handled with tweezers. A vacuum wand with a non-metallic ESD protected tip should be used.

Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the
 assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

Further Information

For further information please contact your local IR Sales office or email your enquiry to http://die.irf.com

Data and specifications subject to change without notice. This product has been designed and qualified for Industrial market.

Qualification Standards can be found on IR's Web site.



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